

FCC EMC TEST REPORT

ISSUED BY
Shenzhen BALUN Technology Co., Ltd.



FOR
smart phone

ISSUED TO
Shenzhen Huadoo Bright Group Limited

Room 13E, jinsong Buiding, Tai ran 4th Rood, chegong miao, Futian
Distrct, Shenzhen



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Date *Dec 31, 2014*

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Wei Yanguan
(Chief Engineer)

Date *Dec 31, 2014*

Report No.: BL-SZ14C0012-401

EUT Type: smart phone

Model Name: Huadoo V4

Brand Name: Huadoo

Test Standard: 47 CFR Part 15 Subpart B

FCC ID: 2ACXS-V4

Test conclusion: PASS

Test Date: Nov 25 2014 ~ Dec 28, 2014

Date of Issue: Dec 31, 2014

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Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Dec 31, 2014</u>	<u>Initial Issue</u>

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1 GENERAL INFORMATION

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6683 3402
Fax Number	+86 755 6182 4271

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Accreditation Certificate	The laboratory has been listed by Industry Canada to perform electromagnetic emission measurements. The recognition numbers of test site are 11524A-1. The laboratory has been listed by US Federal Communications Commission to perform electromagnetic emission measurements. The recognition numbers of test site are 832625. The laboratory has met the requirements of the IAS Accreditation Criteria for Testing Laboratories (AC89), has demonstrated compliance with ISO/IEC Standard 17025:2005. The accreditation certificate number is TL-588. The laboratory is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L6791.
Description	All measurement facilities used to collect the measurement data are located at Block B, FL 1, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China 518055

1.3 Announce

- (1) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (2) The test report is invalid if there is any evidence and/or falsification.
- (3) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (4) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.

2 PRODUCT INFORMATION

2.1 Applicant

Applicant	Shenzhen Huadoo Bright Group Limited
Address	Room 13E, jinsong Buiding, Tai ran 4th Rood, chegong miao, Futian Distrct, Shenzhen

2.2 Manufacturer

Manufacturer	Shenzhen Huadoo Bright Group Limited
Address	Room 13E, jinsong Buiding, Tai ran 4th Rood, chegong miao, Futian Distrct, Shenzhen

2.3 General Description for Equipment under Test (EUT)

EUT Type	smart phone
Model Name	Huadoo V4
Hardware Version	MOLY.WR8.W1315.MD.MG.MP.V39
Software Version	V4_overseas_V5_20141105
The Highest Speed of Processor	1.3GHz
Network and Wireless connectivity	2G Network GSM 850/900/1800/1900, GPRS, EDEG. 3G Network WCDMA Band I/II/V Bluetooth V4.0 Low Energy(BLE), BT 3.0, WIFI
About the Product	The equipment is smart phone, intended for used with information technology equipment.

2.4 Ancillary Equipment

Ancillary Equipment 1	Battery	
	Brand Name	N/A
	Model No	V4
	Serial No	N/A
	Capacitance	3600mAh
	Rated Voltage	3.7V
	Extreme Voltage	Low: 3.3V / High:4.2V
Ancillary Equipment 2	Charger	
	Brand Name	N/A
	Model No	HJ-0501000
	Serial No	N/A
	Rated Input	~ 100-240V, 0.15A, 50/60Hz
	Rated Output	= 5V, 1000mA
Ancillary Equipment 3	Earphone	
	Length	1.0m
Ancillary Equipment 4	USB Data Cable	
	Length	1.0m

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	FCC 47 CFR Part 15 Subpart B (10-1-13 Edition)	Unintentional Radiators
2	ANSI C63.4-2014	American National Standard for Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Result
1	Radiated Emission	15.109	PASS	Annex A .1
2	Conducted Emission, AC Ports	15.107	PASS	Annex A .2

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9KHz-30MHz)	1.12 dB
Radiated emissions (30MHz-1GHz)	2.11 dB
Radiated emissions (1GHz-18GHz)	3.31 dB

4 GENERAL TEST CONFIGURATIONS

4.1 Test Environments

Environment Parameter	Selected Values During Tests			
	Temperature	Voltage	Relative Humidity	Ambient Pressure
Normal Temperature, Normal Voltage (NTNV)	23°C~26°C	AC 230V/50Hz	50%-55%	100 to 102 kPa

4.2 Test Equipment List

Radiated Emission Test						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	ROHDE&SCHWARZ	ESRP	101036	2014.07.07	2015.07.06	☒
Test Antenna-Loop(9kHz-30MHz)	SCHWARZBECK	FMZB 1519	1519-037	2013.07.02	2015.07.01	☒
Test Antenna-Bi-Log(30MHz-3GHz)	SCHWARZBECK	VULB 9163	9163-624	2013.07.03	2015.07.02	☒
Test Antenna-Horn(1-18GHz)	SCHWARZBECK	BBHA 9120D	9120D-1148	2013.07.02	2015.07.01	☒
Test Antenna-Horn(15-26.5GHz)	SCHWARZBECK	BBHA 9170	9170-305	2013.07.02	2015.07.01	☐
Anechoic Chamber	RAINFORD	9m*6m*6m	N/A	2014.10.07	2015.10.06	☒

Conducted disturbance Test						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	ROHDE&SCHWARZ	ESRP	101036	2014.07.07	2015.07.06	☒
LISN	SCHWARZBECK	NSLK 8127	8127-687	2014.07.07	2015.07.06	☒
AMN	SCHWARZBECK	NNBM8124	8124-509	2014.07.07	2015.07.06	☐
AMN	SCHWARZBECK	NNBM8124	8124-510	2014.07.07	2015.07.06	☐
ISN	TESEQ	ISN T800	34449	2014.07.07	2015.07.06	☐
Shielded Enclosure	ChangNing	CN-130701	130703	N/A	N/A	☒

4.3 Test Enclosure list

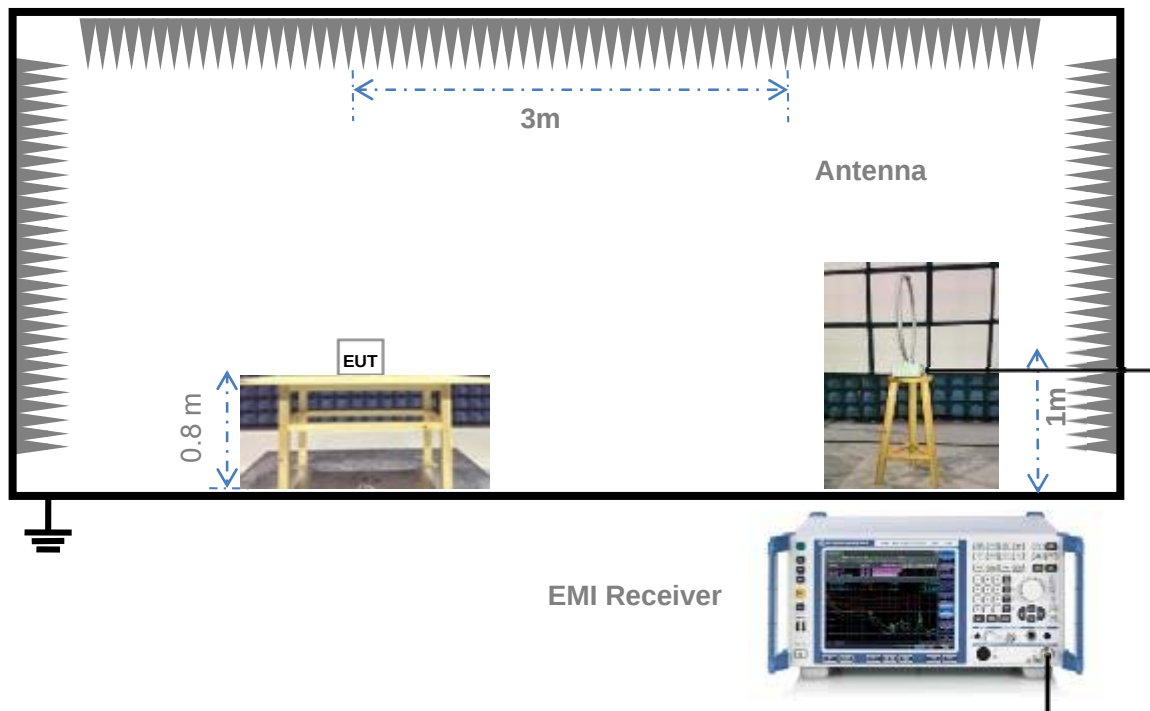
Description	Manufacturer	Model	Serial No.	Length	Description	Use
PC	N/A	N/A	N/A	N/A	Special Handled	☐
Printer	HP	DESKJET 1000	N/A	N/A	N/A	☐
Keyboard	Logitech	Y-BP62a	N/A	N/A	N/A	☐
Mouse	Logitech	M100	N/A	N/A	N/A	☐
USB disk	Kingston	N/A	N/A	N/A	N/A	☐
TF Card	Kingston	N/A	N/A	N/A	N/A	☒
VGA Cable	N/A	N/A	N/A	1.5m	Shielded with core	☐
HDMI Cable	N/A	N/A	N/A	1.5m	Shielded with core	☐
DVI Cable	N/A	N/A	N/A	1.5m	Shielded with core	☐
Coaxial video cable	N/A	N/A	N/A	2m	Shielded with core	☐
Phone	BBK	HCD007TSD	N/A	N/A	N/A	☐
laptop	LENOVO	K29	N/A	N/A	N/A	☒

4.4 Test Configurations

Test Configurations (TC) No.	Description
TC01	<u>The USB Test mode</u> The EUT configuration of the emission tests is TransFlash Card + EUT + Battery + laptop + Earphone. During the measurement, the EUT with a TransFlash Card is connected with the laptop via a USB cable, the data is transmitting between the laptop and the TransFlash Card of the EUT.
TC02	<u>The Camera test mode</u> The EUT configuration of the emission tests is EUT + Battery + Charger + Earphone. During the measurement, the EUT working by way of the Camera.
TC03	<u>The FM test mode</u> The EUT configuration of the emission tests is EUT + Battery + Charger + Earphone. During the measurement, the FM function was active.
TC04	<u>The Idle test mode</u> The EUT configuration of the emission tests is EUT + Battery + Charger + Earphone. During the measurement, the EUT is in the idle test mode and recharged by the AC power.

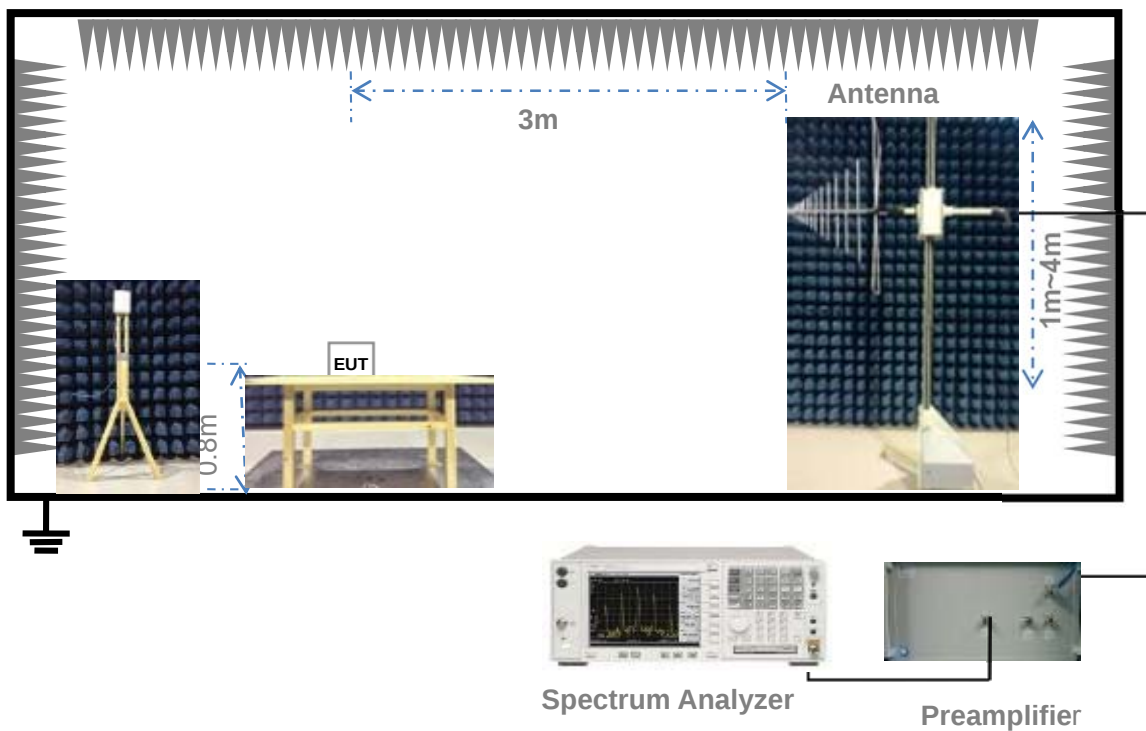
4.5 Test Setups

Test Setup 1



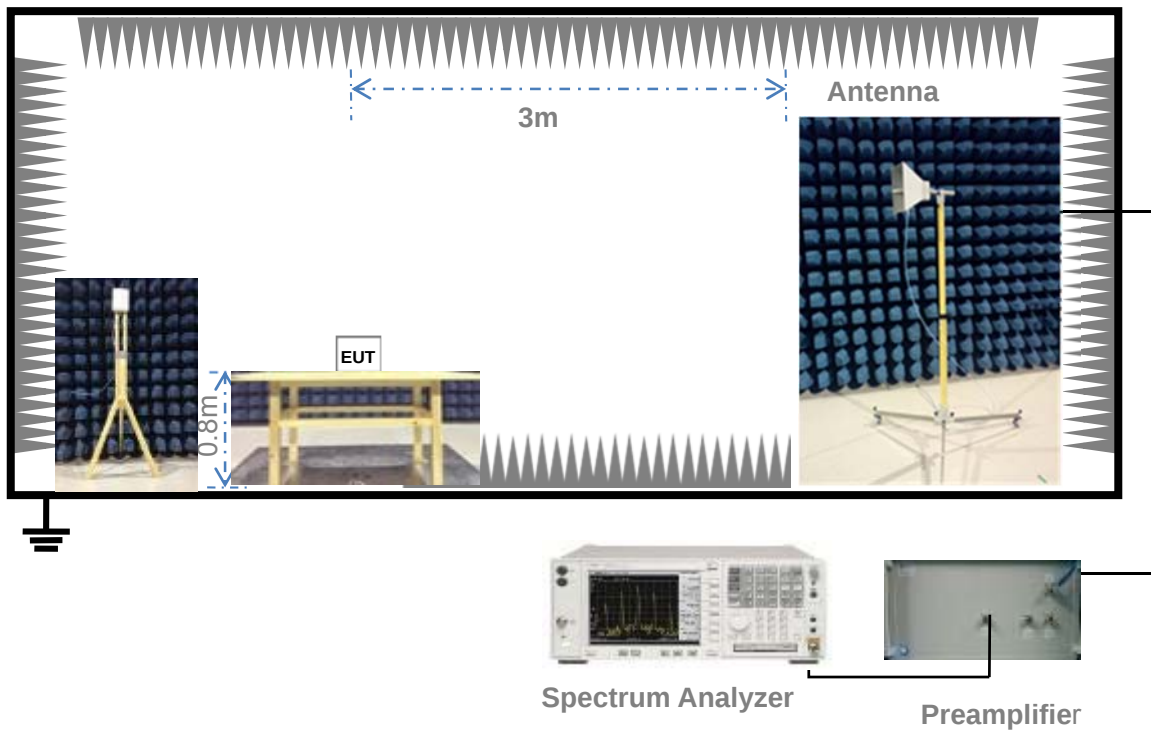
For Radiated Emission Test (Below 30MHz)

Test Setup 2



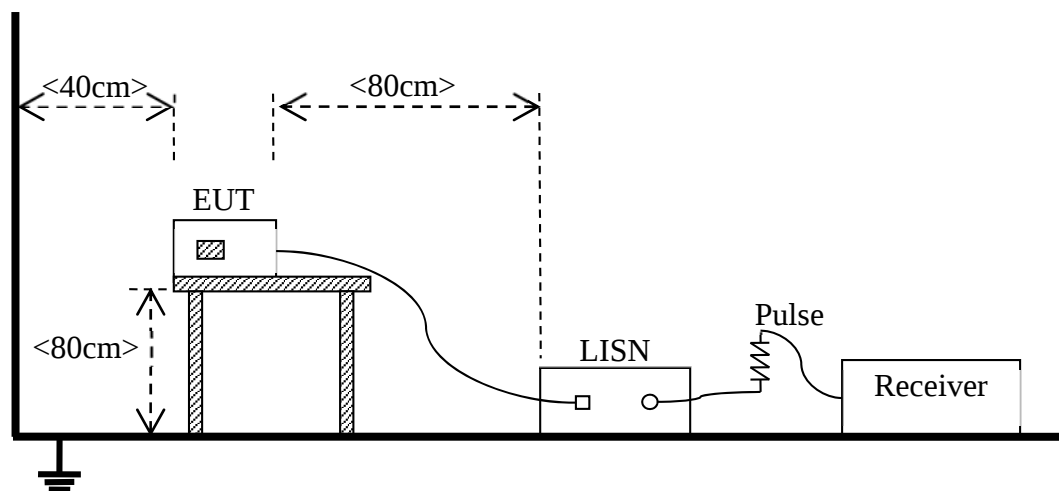
(For Radiated Emission Test (30MHz-1GHz))

Test Setup 3



(For Radiated Emission Test (above 1GHz))

Test Setup 4



(For Conducted Emission, AC Ports Test)

4.6 Test Conditions

Test Case	Test Conditions	
Radiated Emission	Test Env.	NTNV
	Test Setup	Test Setup 1&3
	Test Configuration	TC01~TC04 ^{Note}
Conducted Emission, AC Ports	Test Env.	NTNV
	Test Setup	Test Setup 4
	Test Configuration	TC01~TC04 ^{Note}

Note: Based on client request, all normal using modes of the normal function were tested but only the worst test data of the worst mode is reported by this report. The USB test mode is the worst mode in Radiated Emission test, and the camera test mode is the worst mode in Conducted Emission test.

5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency (MHz)	Field Strength ($\mu\text{V/m}$)	Measurement Distance (m)
0.009 - 0.490	2400/F(kHz)	300
0.490 - 1.705	24000/F(kHz)	30
1.705 - 30.0	30	30
30 - 88	100	3
88 - 216	150	3
216 - 960	200	3
Above 960	500	3

NOTE:

- 1) Field Strength (dB $\mu\text{V/m}$) = $20 \cdot \log[\text{Field Strength } (\mu\text{V/m})]$.
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For above 1000MHz, limit field strength of harmonics: 54dB $\mu\text{V/m}$ @3m (AV) and 74dB $\mu\text{V/m}$ @3m (PK)

5.1.1.2 Test Procedure

All Spurious Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

5.1.2 Conducted Emission

5.1.2.1 Test Limit

Frequency range (MHz)	Conducted Limit (dB μ V)	
	Quasi-peak	Average
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The limit is applicable to Class B ITE.
- 2) The lower limit shall apply at the band edges.
- 3) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50MHz.

5.1.2.2 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. The test frequency range is from 150kHz to 30MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

ANNEX A TEST RESULTS

A.1 Radiated Emission

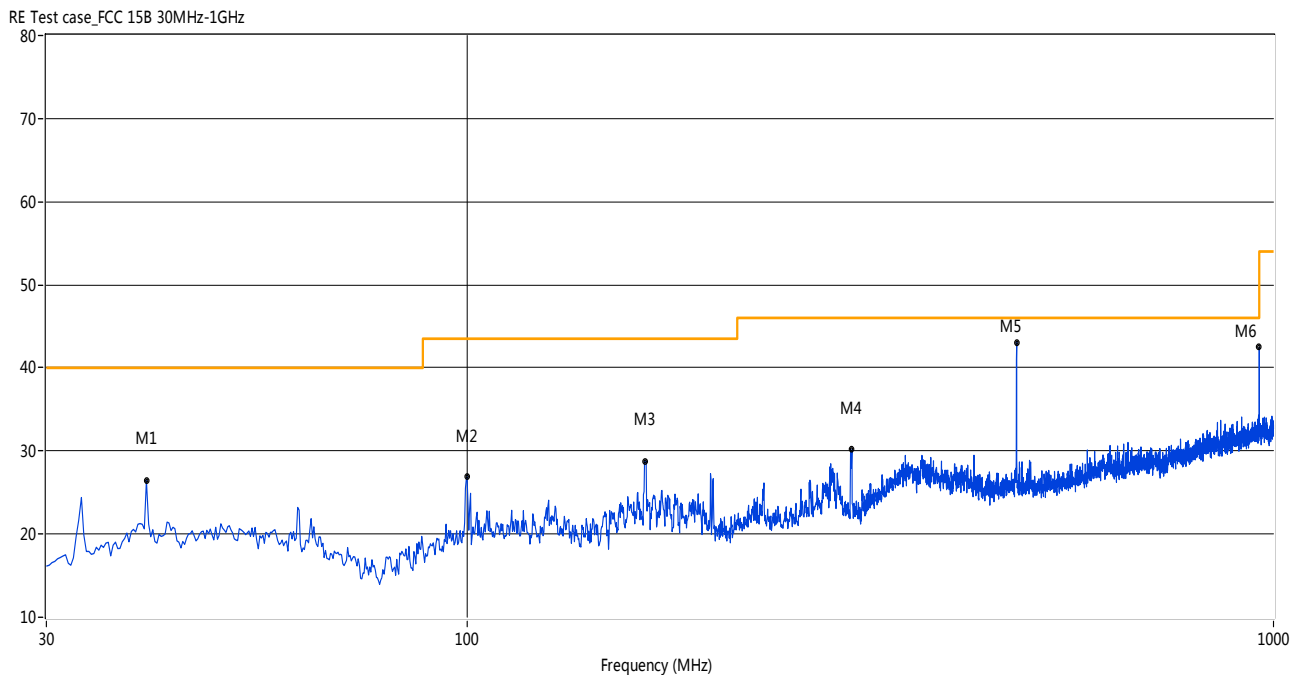
Note 1: The symbol of “--” in the table which means not application.

Note 2: For the test data above 1GHz. According the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Test Data and Plots (USB test mode)

The low frequency, which started from 9 kHz to 30MHz, was pre-scanned and the result which was 20dB lower than the limit line per 15.31(o) was not reported.

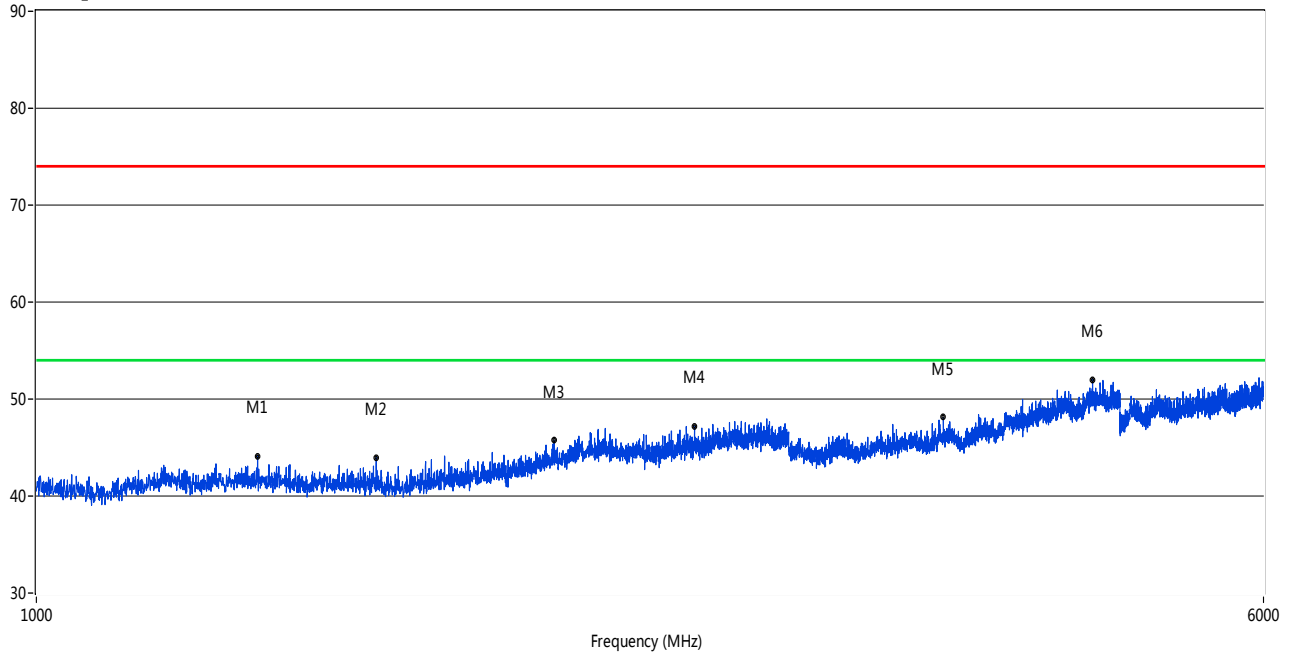
A.1.1 Test Antenna Vertical, 30MHz – 1GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (o)	Height (cm)	ANT	Verdict
1	39.94	26.46	-19.85	40.0	13.54	Peak	25.40	100	Vertical	PASS
2	99.82	26.90	-20.20	43.5	16.60	Peak	276.00	100	Vertical	PASS
3	165.77	28.78	-22.91	43.5	14.72	Peak	59.10	100	Vertical	PASS
4	299.84	30.16	-17.63	46.0	15.84	Peak	359.60	100	Vertical	PASS
5	479.97	43.07	-13.81	46.0	2.93	Peak	75.80	100	Vertical	PASS
6	960.00	42.47	-5.08	46.0	3.53	Peak	314.90	100	Vertical	PASS

A.1.2 Test Antenna Vertical, 1GHz – 6GHz

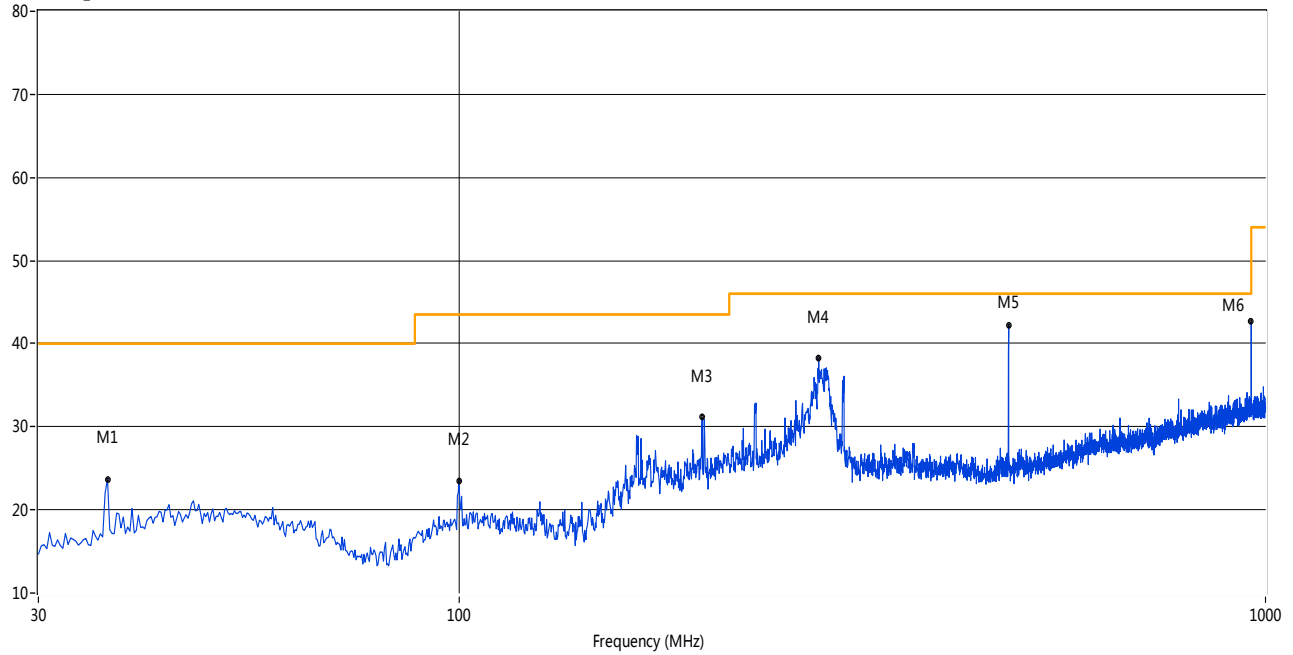
RE Test case_FCC 15B 1GHz-6GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (o)	Height (cm)	ANT	Verdict
1	1381.40	44.13	-4.52	74.0	29.87	Peak	-0.00	100	Vertical	PASS
2	1642.84	44.00	-4.19	74.0	30.00	Peak	210.40	100	Vertical	PASS
3	2129.72	45.74	-1.01	74.0	28.26	Peak	178.50	100	Vertical	PASS
4	2614.10	47.19	0.86	74.0	26.81	Peak	154.70	100	Vertical	PASS
5	3759.56	48.10	10.48	74.0	25.90	Peak	-0.00	100	Vertical	PASS
6	4674.33	52.04	13.16	74.0	21.96	Peak	100.00	100	Vertical	PASS

A.1.3 Test Antenna Horizontal, 30MHz – 1GHz

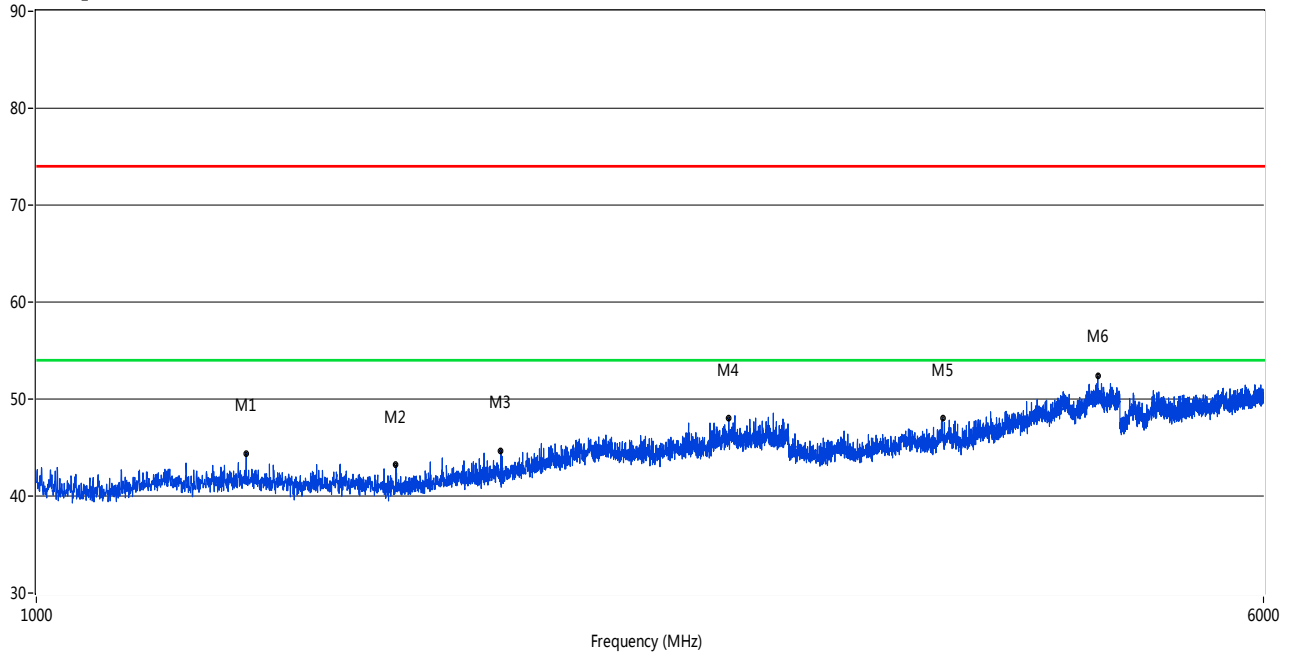
RE Test case_FCC 15B 30MHz-1GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (o)	Height (cm)	ANT	Verdict
1	36.55	23.68	-20.80	40.0	16.32	Peak	294.70	100	Horizontal	PASS
2	99.82	23.52	-20.20	43.5	19.98	Peak	338.60	100	Horizontal	PASS
3	199.95	31.12	-20.22	43.5	12.38	Peak	327.90	100	Horizontal	PASS
4	278.99	38.25	-18.39	46.0	7.75	Peak	194.60	100	Horizontal	PASS
5	479.97	42.28	-13.81	46.0	3.72	Peak	211.60	100	Horizontal	PASS
6	960.00	42.68	-5.08	46.0	3.32	Peak	116.70	100	Horizontal	PASS

A.1.4 Test Antenna Horizontal, 1GHz – 6GHz

RE Test case_FCC 15B 1GHz-6GHz



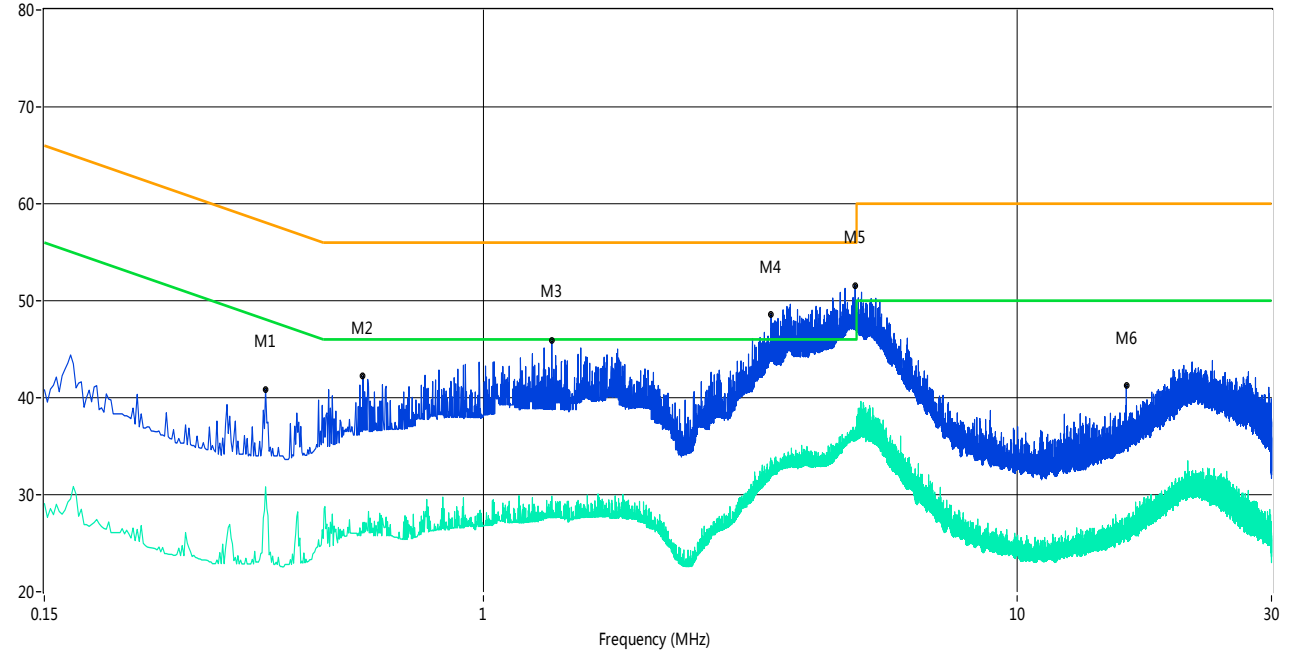
No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (o)	Height (cm)	ANT	Verdict
1	1358.41	44.42	-4.42	74.0	29.58	Peak	331.80	100	Horizontal	PASS
2	1690.83	43.24	-4.24	74.0	30.76	Peak	157.80	100	Horizontal	PASS
3	1970.26	44.68	-2.58	74.0	29.32	Peak	358.50	100	Horizontal	PASS
4	2748.06	48.01	1.64	74.0	25.99	Peak	300.00	100	Horizontal	PASS
5	3755.06	47.96	10.56	74.0	26.04	Peak	154.10	100	Horizontal	PASS
6	4710.32	52.38	13.37	74.0	21.62	Peak	53.80	100	Horizontal	PASS

A.2 Conducted Emission

Test Data and Plots (Camera test mode)

A.2.1 L Phase

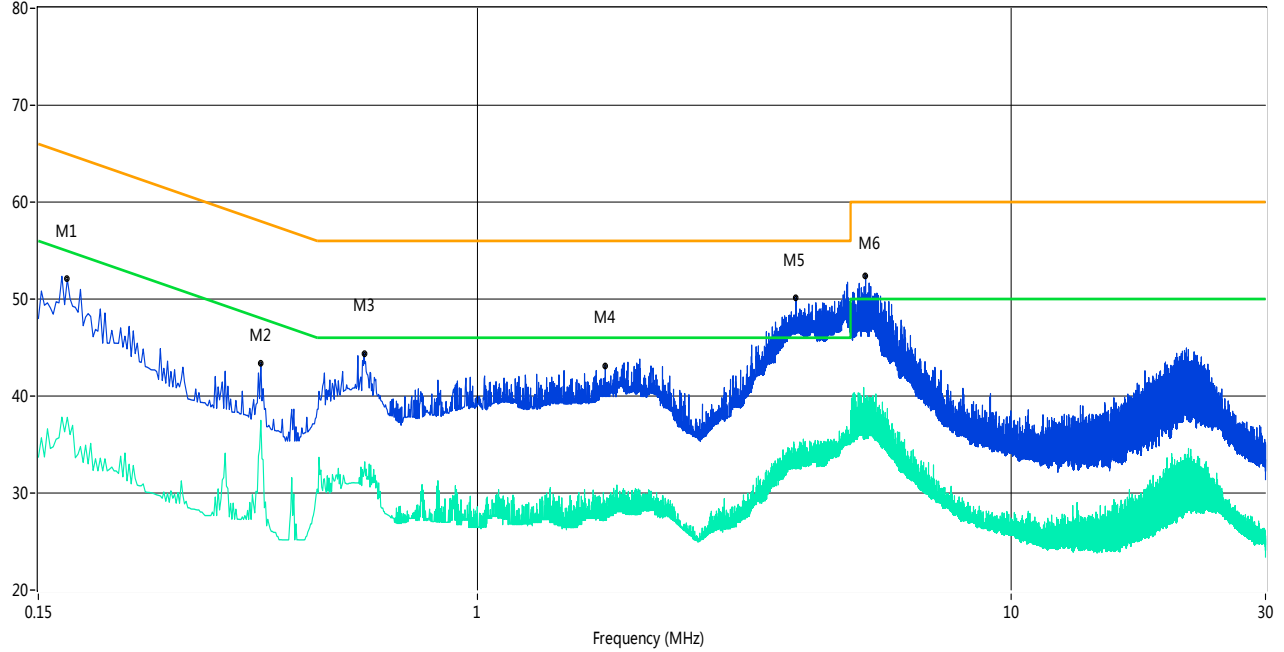
CE Test case_CE_EN 55022_Class B



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.39	40.9	13.00	59.1	18.20	Peak	L Line	PASS
1**	0.39	30.8	13.00	49.1	18.30	AV	L Line	PASS
2	0.59	42.2	13.00	56.0	13.80	Peak	L Line	PASS
2**	0.59	27.1	13.00	46.0	18.90	AV	L Line	PASS
3	1.34	45.9	13.00	56.0	10.10	Peak	L Line	PASS
3**	1.34	29.8	13.00	46.0	16.20	AV	L Line	PASS
4	3.46	48.6	13.00	56.0	7.40	Peak	L Line	PASS
4**	3.46	33.1	13.00	46.0	12.90	AV	L Line	PASS
5	4.97	51.6	13.00	56.0	4.40	Peak	L Line	PASS
5**	4.97	36.3	13.00	46.0	9.70	AV	L Line	PASS
6	16.03	41.2	13.00	60.0	18.80	Peak	L Line	PASS
6**	16.03	25.4	13.00	50.0	24.60	AV	L Line	PASS

A.2.2 N Phase

CE Test case_CE_EN 55022_ Class B



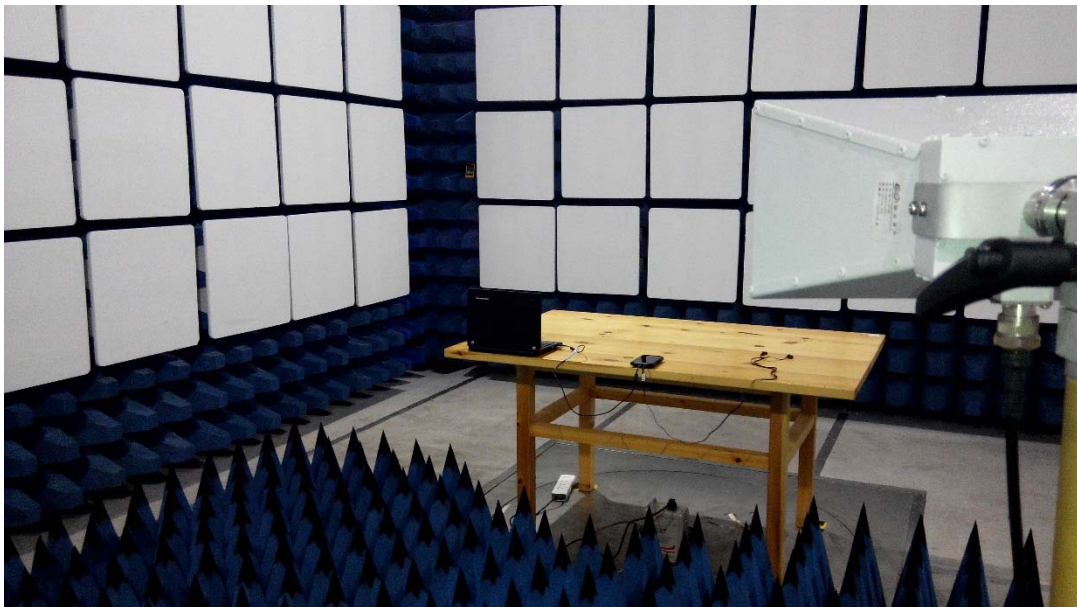
No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.17	52.1	13.00	65.4	13.30	Peak	N Line	PASS
1**	0.17	37.8	13.00	55.4	17.60	AV	N Line	PASS
2	0.39	43.4	13.00	59.1	15.70	Peak	N Line	PASS
2**	0.39	37.5	13.00	49.1	11.60	AV	N Line	PASS
3	0.61	44.4	13.00	56.0	11.60	Peak	N Line	PASS
3**	0.61	32.2	13.00	46.0	13.80	AV	N Line	PASS
4	1.73	43.1	13.00	56.0	12.90	Peak	N Line	PASS
4**	1.73	28.8	13.00	46.0	17.20	AV	N Line	PASS
5	3.95	50.2	13.00	56.0	5.80	Peak	N Line	PASS
5**	3.95	33.5	13.00	46.0	12.50	AV	N Line	PASS
6	5.33	52.4	13.00	60.0	7.60	Peak	N Line	PASS
6**	5.33	35.5	13.00	50.0	14.50	AV	N Line	PASS

ANNEX B TEST SETUP PHOTOS

B.1 Radiated Field Strength Measurement

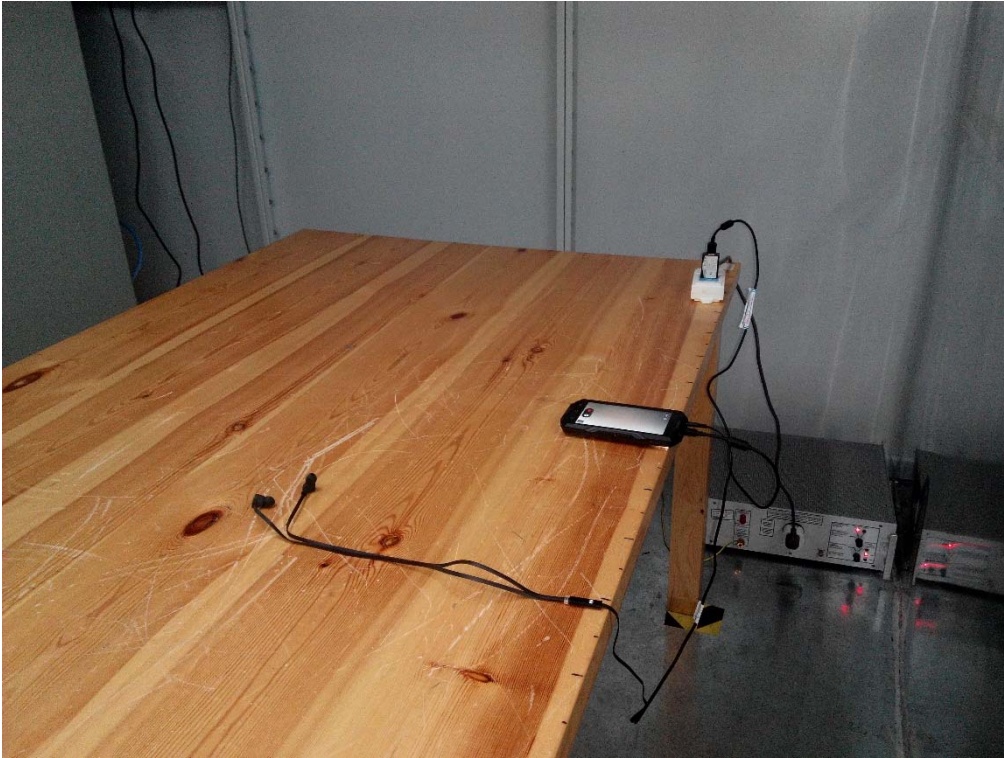


30MHz-1GHz (USB test mode)



Above 1GHz (USB test mode)

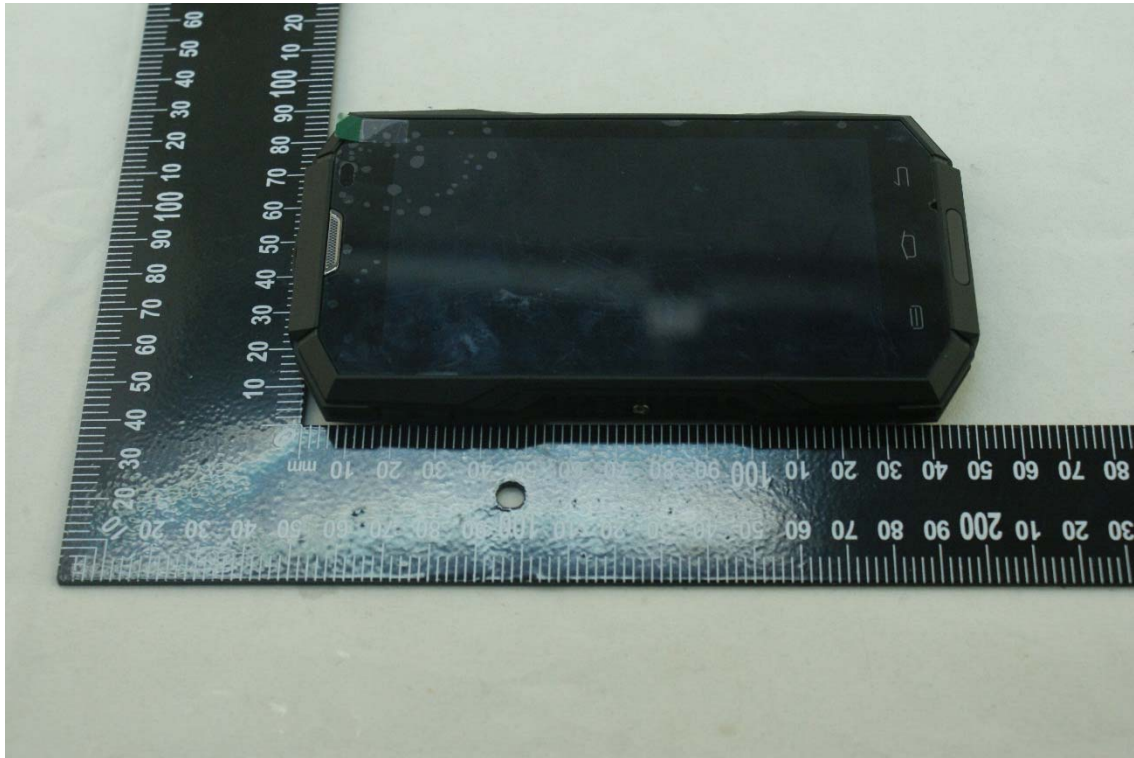
B.2 Conducted Emission



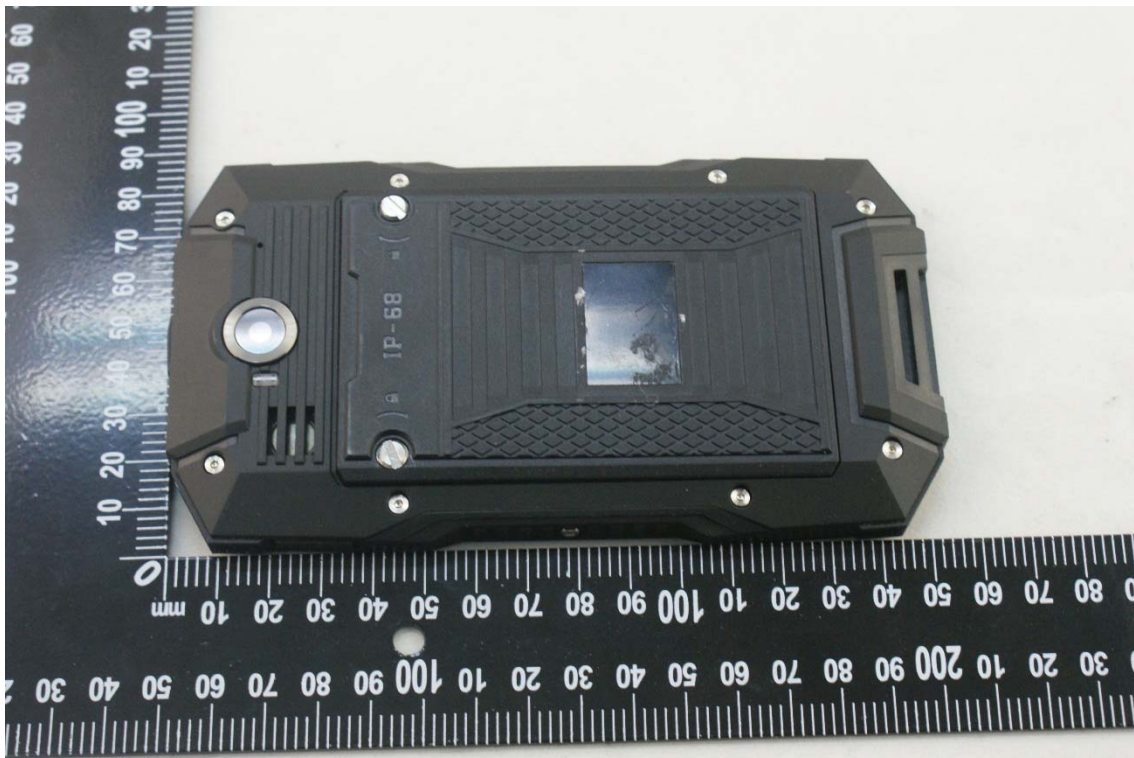
Camera test mode

ANNEX C EUT PHOTOS

C.1 Appearance of the EUT



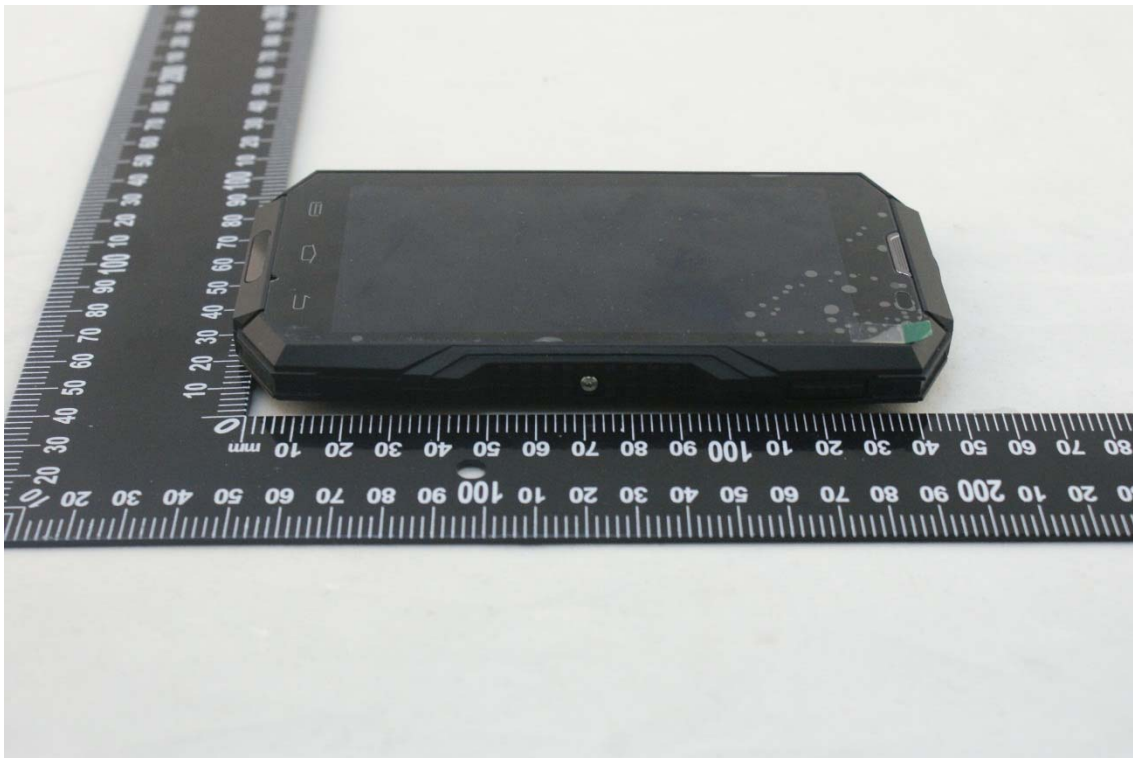
THE FRONT OF EUT



THE BACK OF EUT



THE LEFT OF EUT



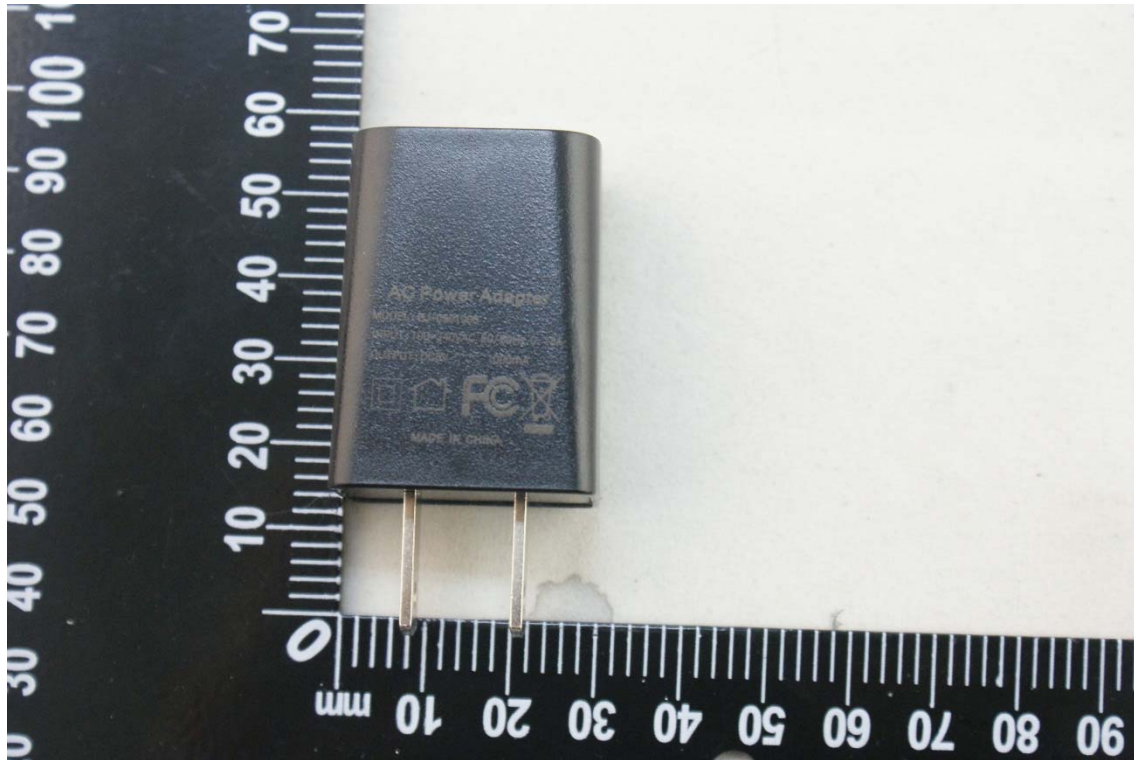
THE RIGHT OF EUT



THE UP OF EUT



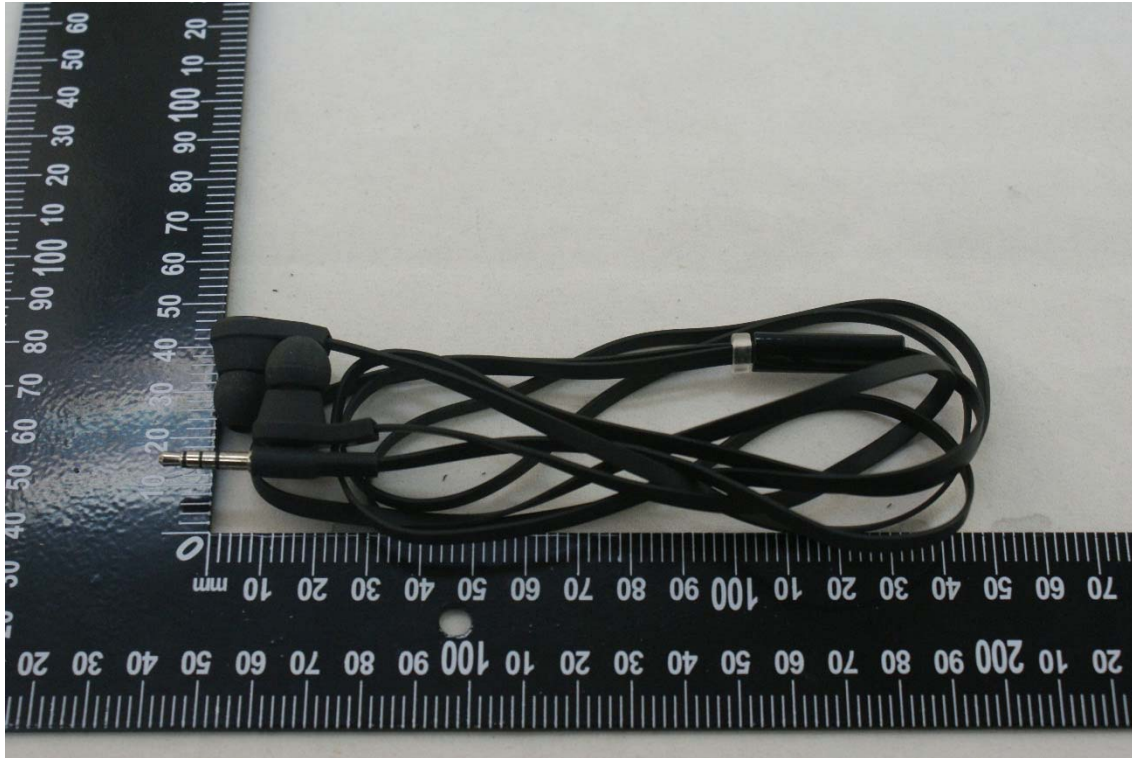
THE DOWN OF EUT



CHARGER

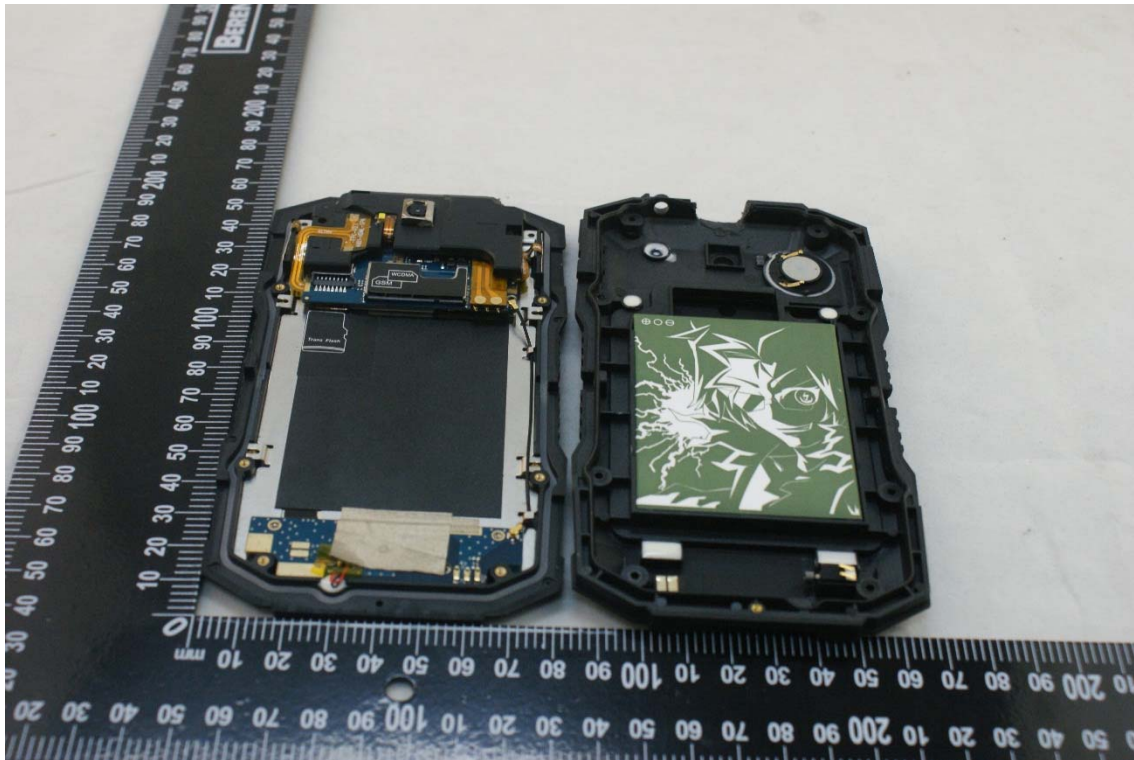


USB CABLE

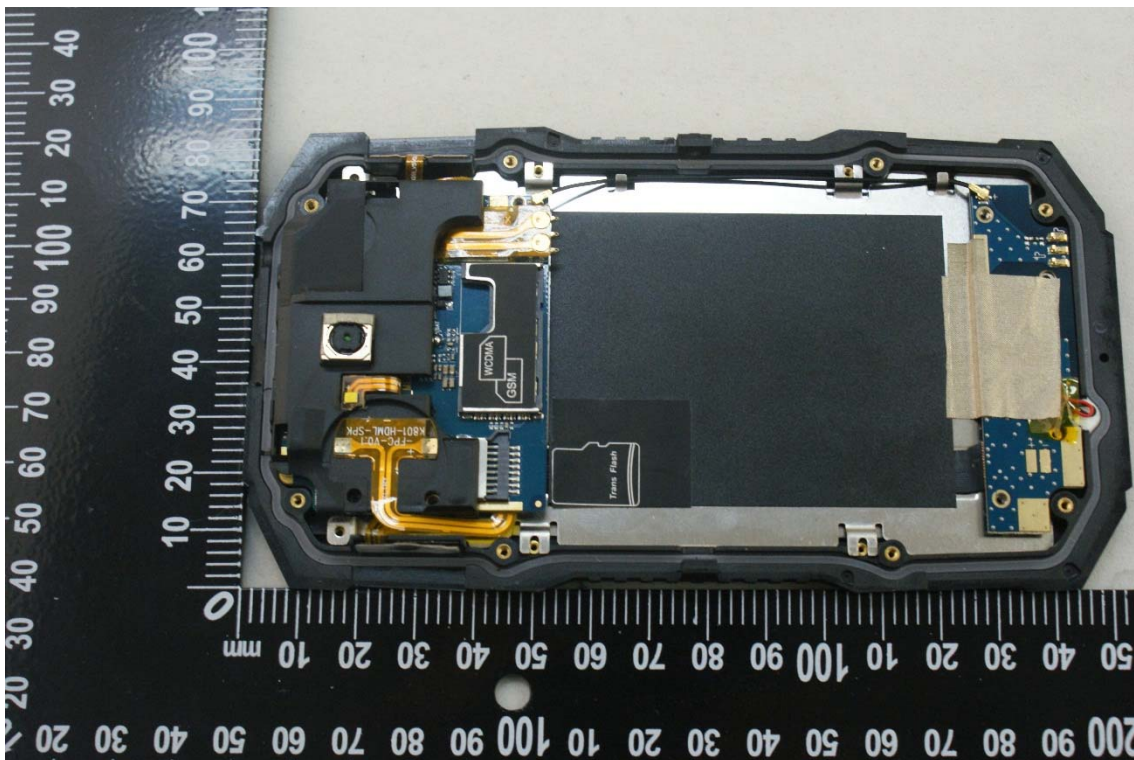


EARPHONE

C.2 Inside of the EUT



EUT UNCOVER VIEW 1



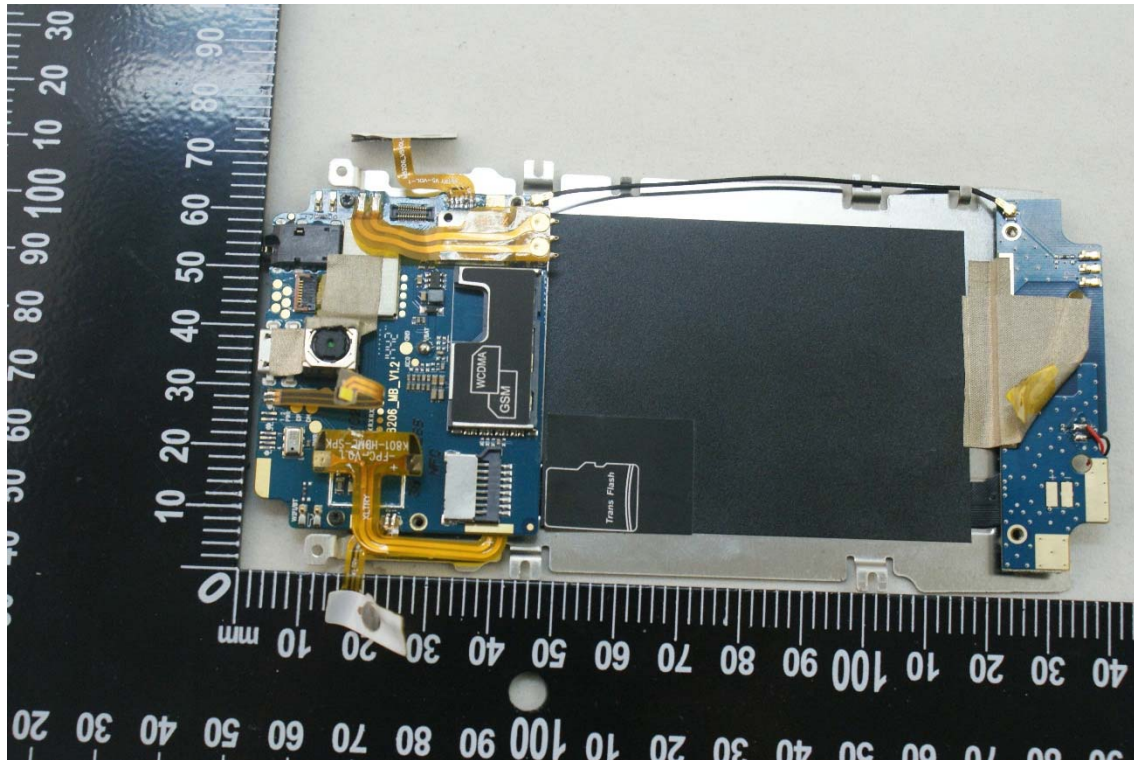
EUT UNCOVER VIEW 2



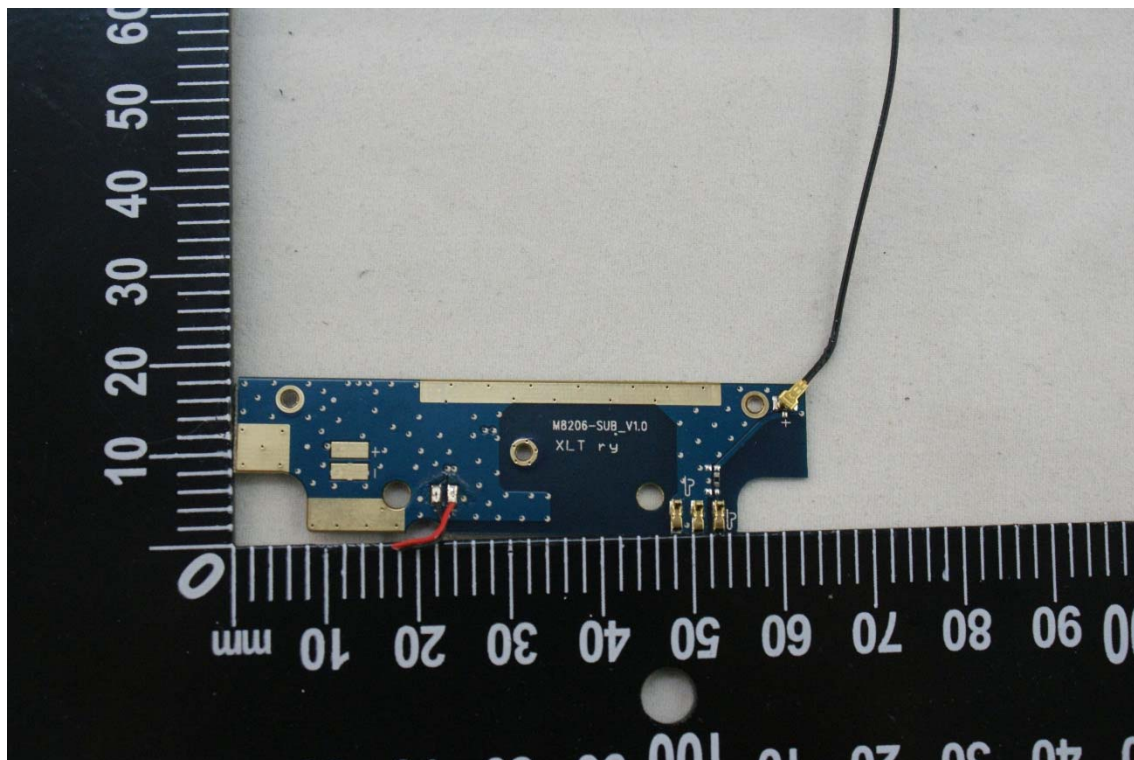
EUT UNCOVER VIEW 3



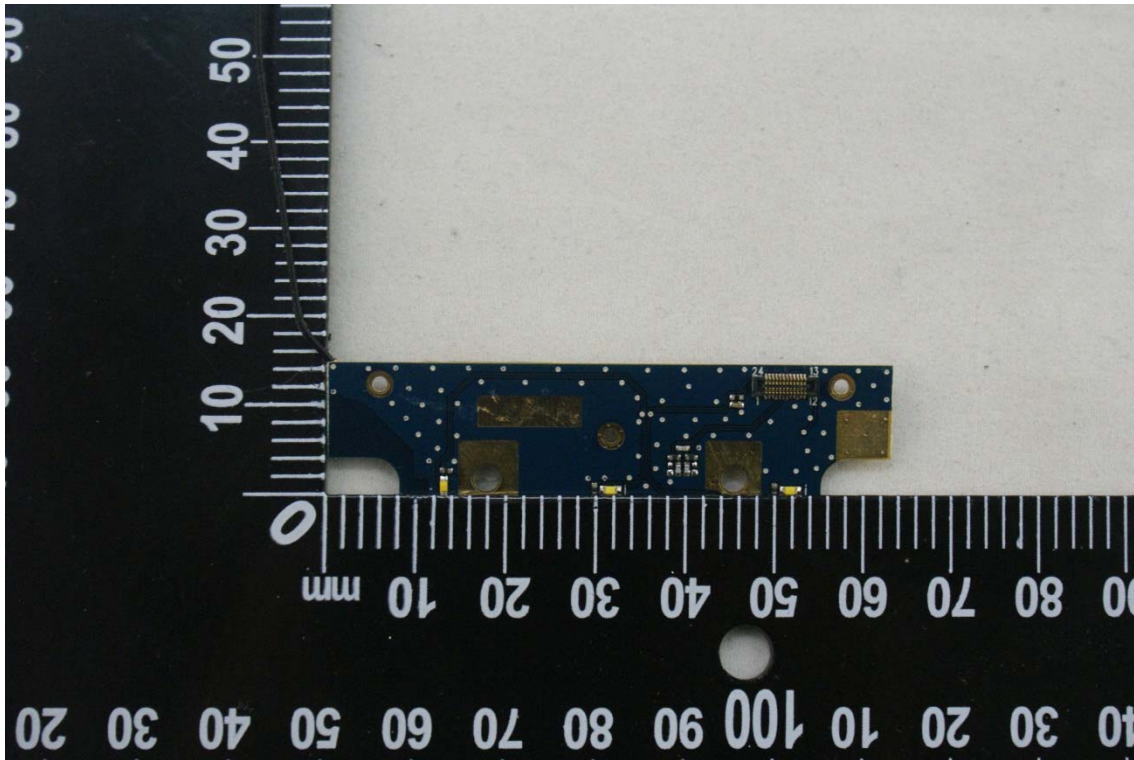
BATTERY



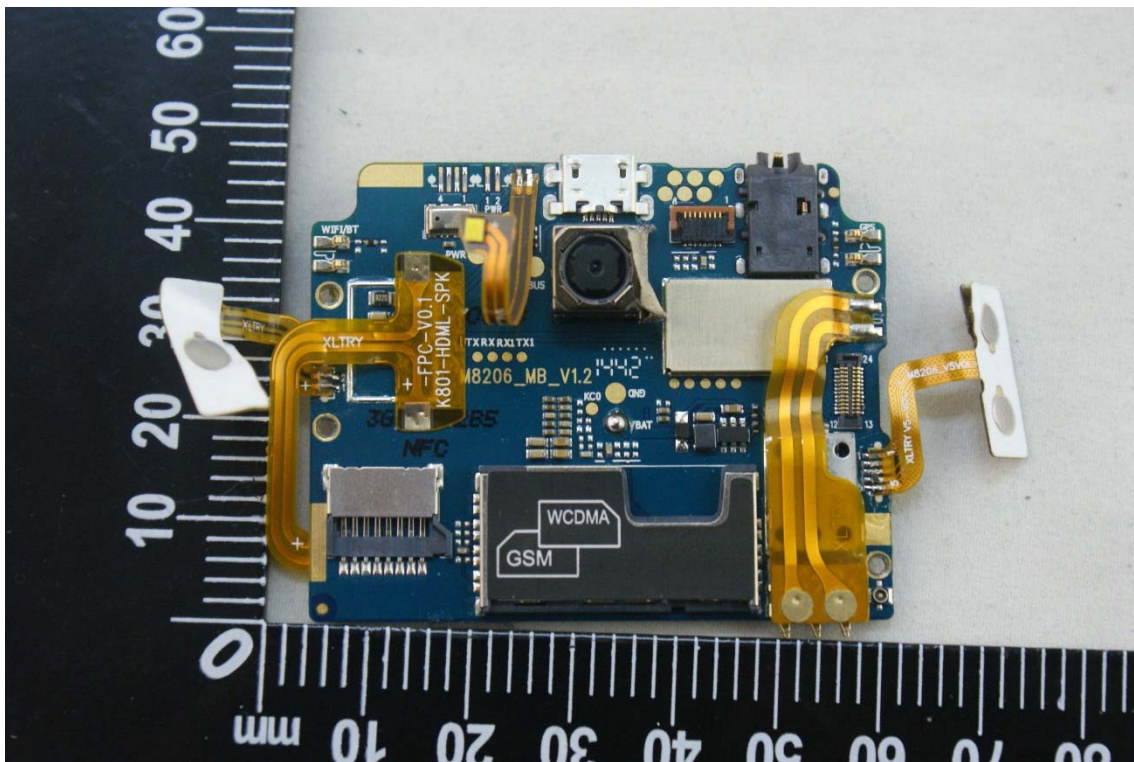
MAIN BOARD TOP VIEW 1



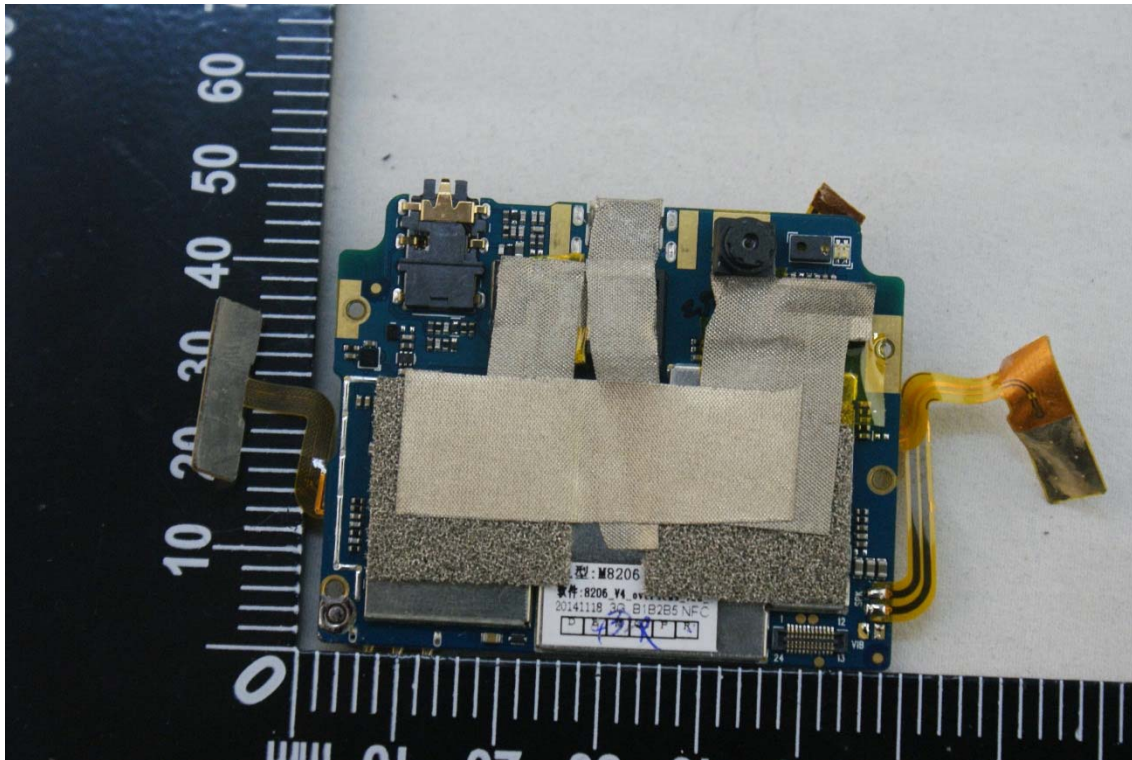
MAIN BOARD TOP VIEW 2



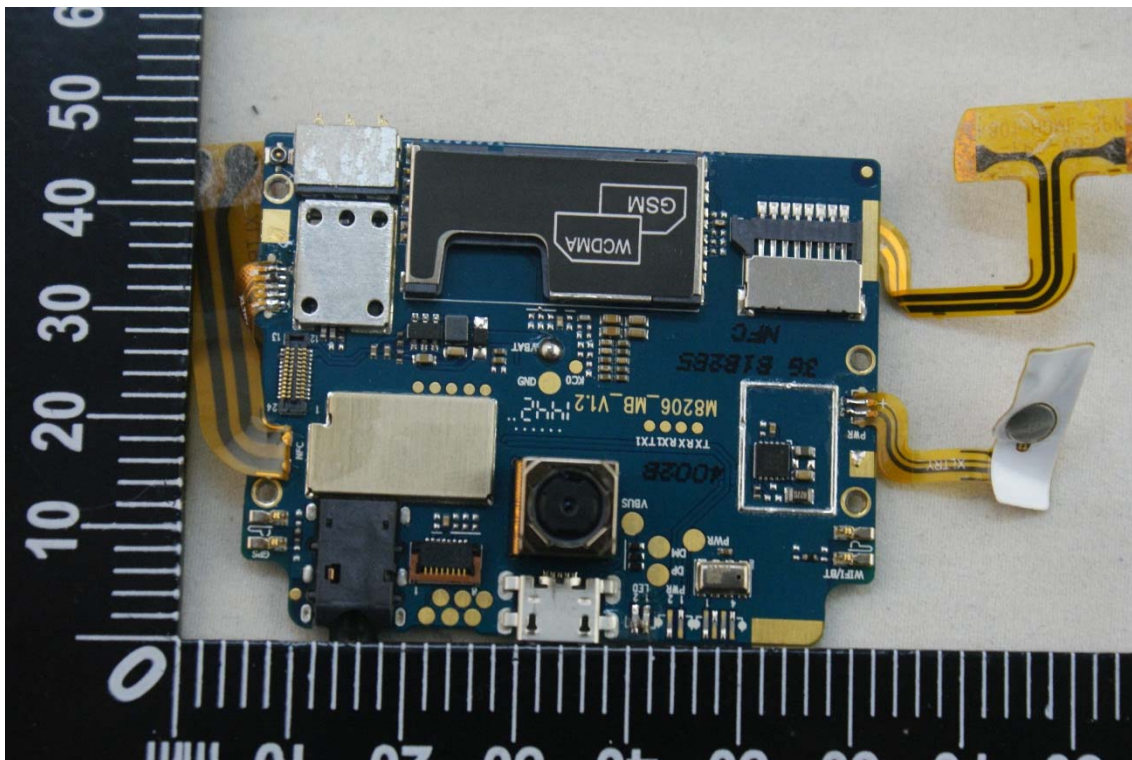
MAIN BOARD BACK VIEW 2



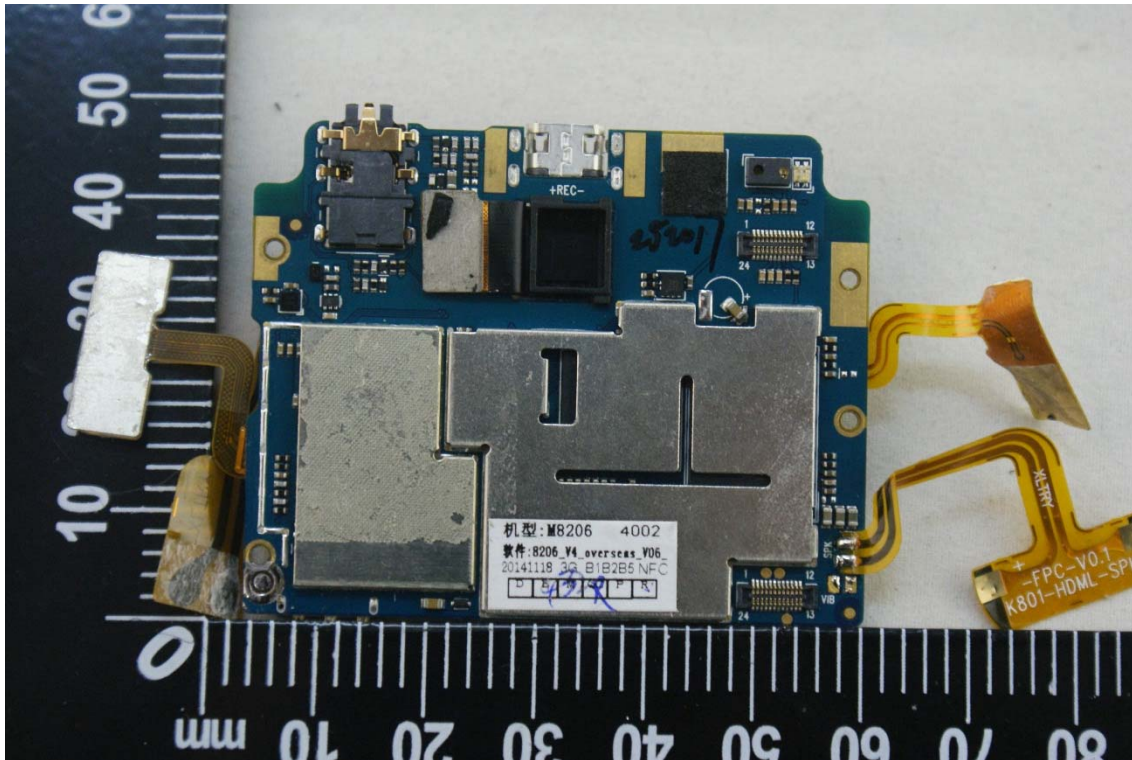
MAIN BOARD TOP VIEW 3



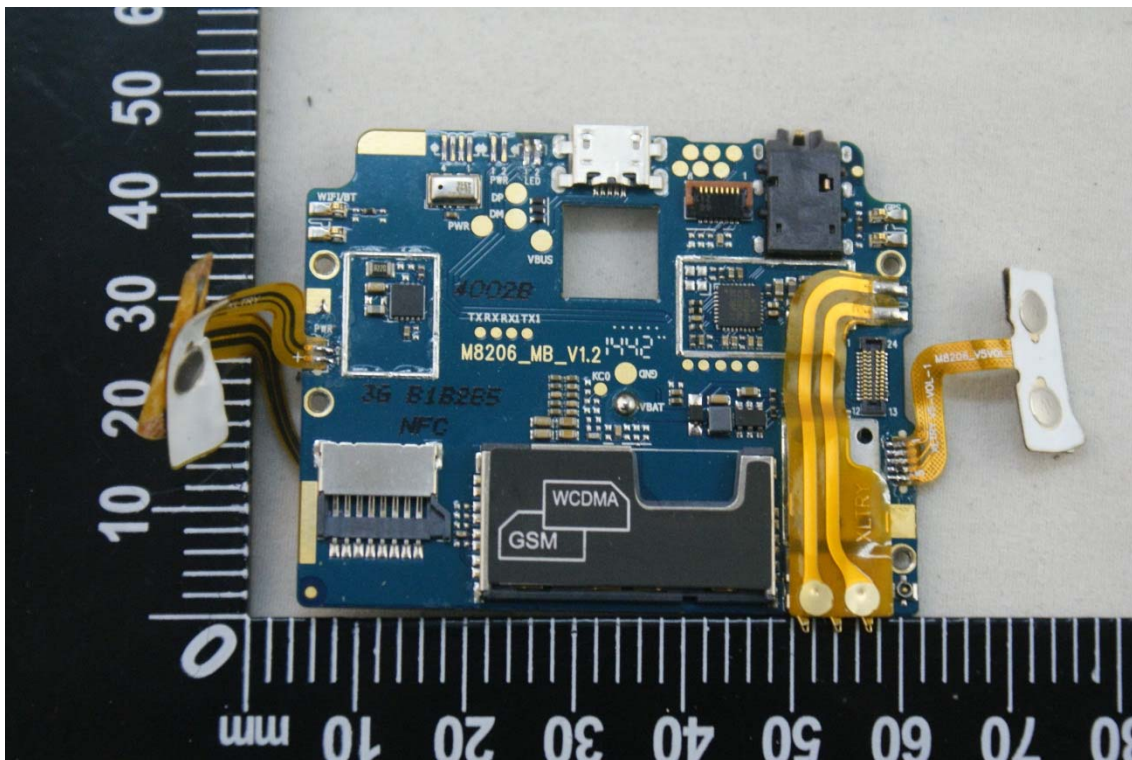
MAIN BOARD BACK VIEW 3



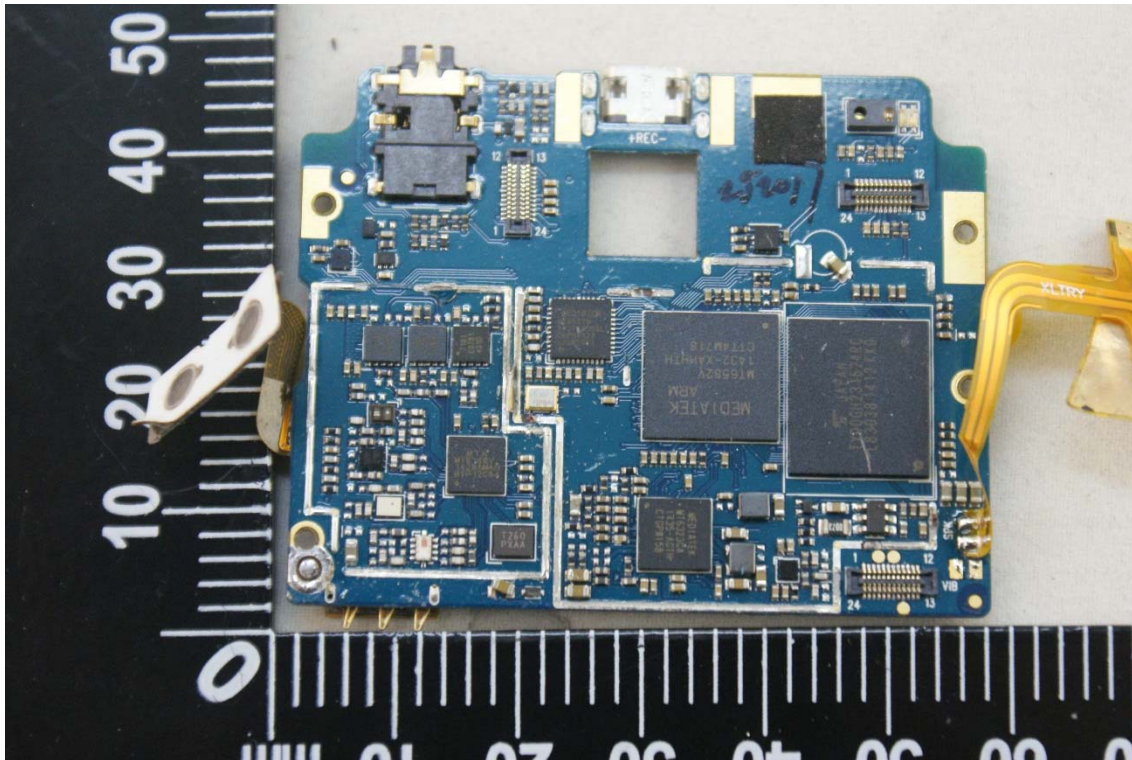
MAIN BOARD TOP VIEW 4



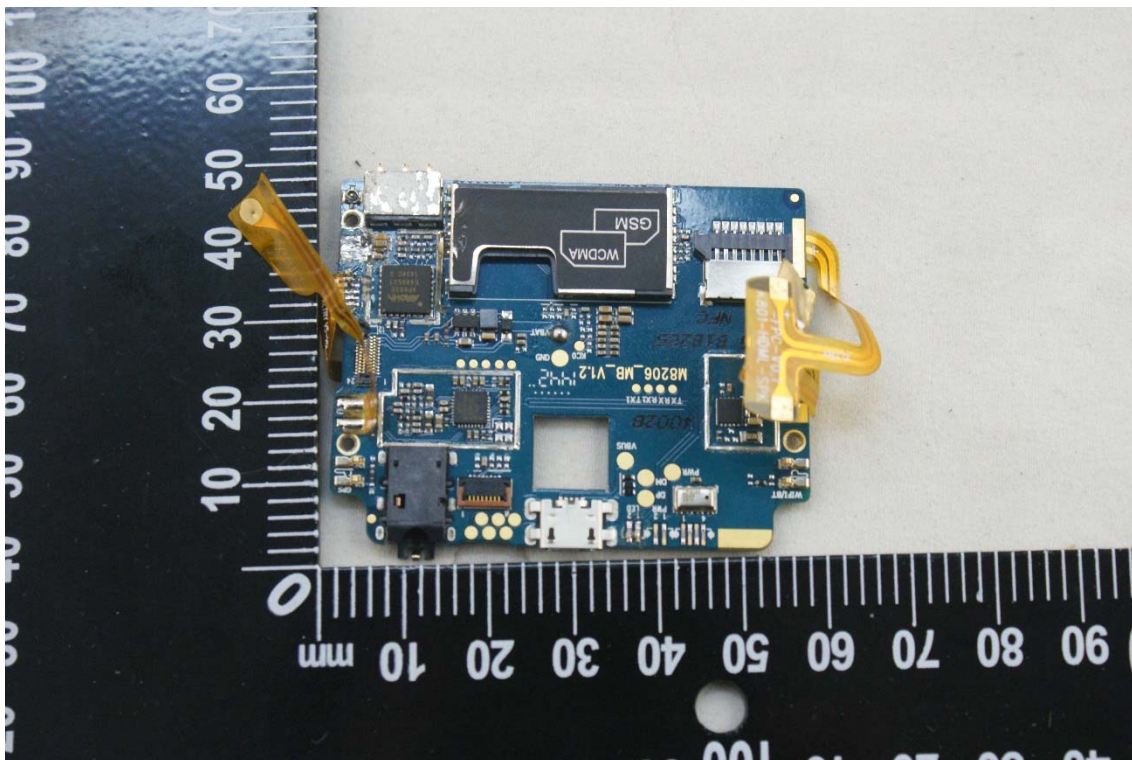
MAIN BOARD BACK VIEW 4



MAIN BOARD TOP VIEW 5



MAIN BOARD BACK VIEW 5



MAIN BOARD TOP VIEW 6

--END OF REPORT--